

What is claimed is:

[Claim 1] 1. A method for fabricating a dual-bit non-volatile memory cell, the method comprising:

forming a dummy gate, having an upper surface and two sidewalls, on a substrate;

forming a stack of layers, having at least an oxide silicon layer and a silicon nitride layer overlying the oxide silicon layer, on the upper surface and two sidewalls of the dummy gate and exposed portions of the substrate;

forming a dummy oxide overlying the stack of layers;

etching a portion of the dummy oxide, a portion of the stack of layers on the two sidewalls of the dummy gate, and a portion of the dummy gate using a first etching process, wherein the bottom of the silicon nitride layer is utilized as a stop layer;

removing the dummy gate such that the stack of layers has a first opening to expose a portion of the substrate;

forming a gate oxide layer on the first opening such that the gate oxide layer has a recess within the first opening;

forming a first polysilicon layer on the gate oxide layer;

forming a control gate on the recess using the first polysilicon layer;

forming a second oxide silicon layer on the surface of the control gate and the stack of the layers;

forming a second polysilicon layer on the second oxide silicon layer; and

performing a self-aligned etching to anisotropically etch the second polysilicon layer to form dual split-gates on the second oxide silicon layer, separated from the control gate by the second oxide silicon layer.

[Claim 2] 2. The method of claim 1 wherein portions of the dummy oxide, the stack of layers, and the dummy gate are removed before the first etching process.

[Claim 3] 3. The method of claim 2 wherein removal of the portions of the dummy oxide, the stack of layers, and the dummy gate before the first etching process is performed by chemical mechanical polishing (CMP).

[Claim 4] 4. The method of claim 2 wherein removal of the portions of the dummy oxide, the stack of layers, and the dummy gate before the first etching process is performed by etching back.

[Claim 5] 5. The method of claim 1 wherein the bottom of the silicon nitride layer is defined as being on and substantially parallel to the substrate.

[Claim 6] 6. The method of claim 1 wherein the substrate comprises a drain region and a source region, each of the regions uniquely corresponding to one of the split-gates.

[Claim 7] 7. The method of claim 1 wherein the dummy gate is formed using a mask used for forming the control gate.

[Claim 8] 8. The method of claim 1 wherein the first etching process is performed by dry etching.

[Claim 9] 9. The method of claim 1 wherein the dummy gate is made from silicon dioxide.

[Claim 10] 10. A dual-bit non-volatile memory cell, the dual-bit non-volatile memory cell comprising:

a stack of layers on a surface of a substrate, the substrate having at least one first oxide silicon layer and a silicon nitride layer overlying the first oxide silicon layer, the stack of layers having a opening exposing a portion of the substrate;

a gate oxide layer on the surface of the substrate within the opening;

a control gate on the gate oxide layer;
a second oxide silicon layer overlying a portion of the surface of the control gate, a portion of the gate oxide layer, and the stack of layers; and
dual split-gates on the second oxide silicon layer, separated from the control gate by the second oxide silicon layer.

[Claim 11] 11. The dual-bit non-volatile memory cell of claim 10 wherein the substrate comprises a drain region and a source region, each of the regions uniquely corresponding to one of the split-gates.